

3-TERMINAL 0.1A POSITIVE VOLTAGE REGULATORS

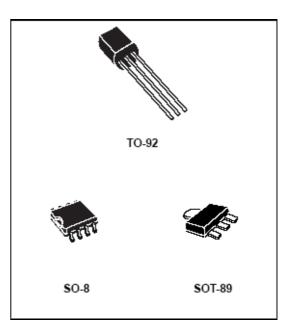
This series of fixed-voltage monolithic integrated-circuit voltage regulators is designed for a wide range of applications. These applications include on-card regulation for elimination of noise and distribution problems associated with single-point regulation. In addition, they can be used with power-pass elements to make high current voltage regulators. Each of these regulators can deliver up to 100mA output current.

The internal limiting and thermal shutdown features of these regulators make them essentially immune to overload.

When used as a replacement for a zener diode-resistor combination, an effective improvement in output impedance can be obtained together with lower-bias current.

Features

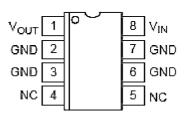
- Output current Up to 100mA
- No External Components
- Internal Thermal Overload Protection
- •Internal Short-Circuit Limiting
- Output Voltage of 5V, 6V, 8V, 9V, 10V, 12V, 15V, 18V and 24V



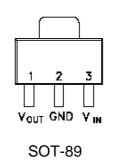
ORDERING INFORMATION

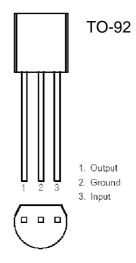
Device	Operating Temperature Range	Package	Packing
HT78LXXATZ	T 1001 1050 0	TO-92	Bulk
HT78LXXARTZ		TO-92	Taping
HT78LXXARZ	T _A = -40° to 125° C	SO-8	Tape & Reel
HT78LXXARSZ		SOT-89	Tape & Reel

Pin Configuration



SO-8







Absolute Maximum Ratings

Charac	teristic	Symbol	Value	Unit
	HT78L05 ~ HT78L10		20	
Input voltage	HT78L12 ~ HT78L18	VI	35	V
	HT78L24		40	
	TO-92		625	
Power Dissipation	SOT-89	Pd	500	mW
	SOP-8		625	
Operating junction ter	mperature	Topr	-40 ~ +150	
Storage temperature		Tstg	-65 ~ +150	°C
Soldering temperatur	e and time	Tsol	260/10sec	

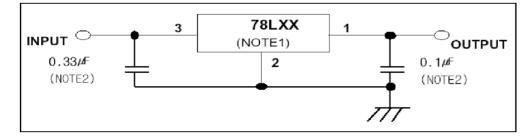
* Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

7	8Lxx	Min.	Max.	Unit
	HT78L05	7	20	
	HT78L06	8	20	
	HT78L08	10.5	23	
	HT78L09	11.5	24	
Input voltage, VI	HT78L10	12.5	25	V
	HT78L12	14.5	27	
	HT78L15	17.5	30	
	HT78L18	20.5	33	
	HT78L24	26.5	39	
Output current, lo	Output current, lo		100	mA
Operating virtual junction ter	nperature, Tj	-40	125	°C

TYPICAL APPLICATION



Notes

- 1. To specify an output voltage, substitute voltage for "XX"
- 2. Bypass capacitors are recommended for optimum stability and transient response
- and should be located as close as possible to the regulators.



HT78L05 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=10V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test condi	tion *	Min	Тур.	Max.	Unit
		25°C		4.8	5	5.2	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 7V≤ VI≤ Vmax	-40 ~ 125℃	4.75	5	5.25	V
		1 mA≤lo≤ 70 mA		4.75	5	5.25	
Line regulation	Reg line	7≤ VI≤ 20V	25℃		32	150	mV
Line regulation	8≤ VI≤ 20V		26	100	ШV		
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25°C		15	60	mV
Load regulation	rteg load	1 mA≤ lo≤ 40 mA			8	30	
Bias current	IB		25°C		3.8	6	mA
bias current	в		125°C			5.5	IIIA
Bias current change	ΔI _B	9≤ VI≤ 20V	-40 ~ 125℃			1.5	۳Å
blas current change	ΔB	1 mA≤ lo≤ 40 mA	-40 ~ 123 C			0.1	mA
Output noise voltage	V	10 Hz≤ f≤ 100 kHz	25°C		42		μN
Ripple rejection	RR	8≤ VI≤ 20V f=120 Hz	25℃	41	49		dB
Dropout voltage	VD		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L06 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=12V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test condi	ition *	Min	Тур.	Max.	Unit
			25°C	5.75	6	6.25	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 8V≤ VI≤ 20V	-40 ~ 125°C	5.7	6	6.3	V
		1 mA≤lo≤ 70 mA		5.7	6	6.3	
Line regulation	Reg line	8≤ VI≤ 20V	/l≤ 20V 25°C		35	175	m\/
	Regime	9≤ VI≤ 20V		29	125	mV	
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25°C		16	80	mV
Load regulation	Neg load	1 mA≤ lo≤ 40 mA			9	40	
Bias current	IB		25°C		3.9	6	mA
bias current	в		125°C			5.5	IIIA
Bias current change	ΔI _B	9≤ VI≤ 20V	-40 ~ 125℃			1.5	۳۸
blas current change	ΔB	1 mA≤ lo≤ 40 mA	-40 ~ 125 C			0.1	- mA
Output noise voltage	V	10 Hz≤ f≤ 100 kHz	25°C		46		μN
Ripple rejection	RR	9≤ VI≤ 19V f=120 Hz	25℃	40	48		dB
Dropout voltage	VD		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L08 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=14V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25°C	7.7	8	8.3	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 10.5V≤ VI≤ 23V	-40 ~ 125℃	7.6	8	8.4	V
		1 mA≤lo≤ 70 mA		7.6	8	8.4	
Line regulation	Reg line	10.5≤ VI≤ 23V	25°C		42	175	m\/
	Regime	11≤ VI≤ 23V		36	125	- mV	
Load regulation R	Reg load	1 mA≤ lo≤ 100 mA	25°C		18	80	mV
	Key load	1 mA≤ lo≤ 40 mA	230		10	40	
	1		25°C		4	6	
Bias current	В		125°C			5.5	mA
Diag gurrant change	ΔIB	11≤ VI≤ 23V	-40 ~ 125℃			1.5	
Bias current change	ΔIB	1 mA≤ lo≤ 40 mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kHz	25°C		54		μN
Ripple rejection	RR	13≤ VI≤ 23V f=120 Hz	25℃	37	46		dB
Dropout voltage	V		25℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L09 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=14V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25°C	806	9	9.4	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 12V≤ VI≤ 24V	-40 ~ 125℃	8.55	9	9.45	V
		1 mA≤lo≤ 70 mA		8.55	9	9.45	
Line regulation	Reg line	12≤ VI≤ 24V	25°C		45	175	m\/
Line regulation	Regime	13≤ VI≤ 24V	25°C		40	125	. mV
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25°C .		19	90	mV
	Rogioud	1 mA≤ lo≤ 40 mA			11	40	
	1		25°C		4.1	6	
Bias current	B		125°C			5.5	mA
Bias current change	∆I _B	13≤ VI≤ 24V	-40 ~ 125℃			1.5	۳Å
bias current change	ΔIB	1 mA≤ lo≤ 40 mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kHz	25°C		58		μN
Ripple rejection	RR	13≤ VI≤ 23V f=120 Hz	25℃	38	45		dB
Dropout voltage	V		25℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L10 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=16V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test condi	tion *	Min	Тур.	Max.	Unit
			25°C	9.6	10	10.4	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 13V≤ VI≤ 25V	-40 ~ 125°C	9.5	10	10.5	V
	1 mA≤lo≤ 70 mA		9.5	10	10.5		
Line regulation	Reg line	13≤ VI≤ 25V	25℃ -		51	175	mV
Line regulation	Regime	14≤ VI≤ 25V			42	125	mv
Load regulation Reg	Reg load	1 mA≤ lo≤ 100 mA	25°C .		20	90	. mV
	Neg load	1 mA≤ lo≤ 40 mA			11	40	
	1		25°C		4.2	6	
Bias current	B		125°C			5.5	mA
Bias current change	ΔI _B	14≤ VI≤ 25V	-40 ~ 125℃			1.5	mA
blas current change	ΔB	1 mA≤ lo≤ 40 mA	-40 ~ 123 C			0.1	IIIA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kHz	25°C		62		μN
Ripple rejection	RR	15≤ VI≤ 25V f=120 Hz	25°C	37	44		dB
Dropout voltage	VD		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L12 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=17V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test condi	ition *	Min	Тур.	Max.	Unit
			25°C	11.5	12	12.5	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 14V≤ VI≤ 27V	-40 ~ 125℃	11.4	12	12.6	V
		1 mA≤lo≤ 70 mA	11.4	12	12.6		
Line regulation	Reg line	14.5≤ VI≤ 27V	25°C –		55	250	mV
	Neg line	16≤ VI≤ 27V			49	200	mv
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25℃ .		22	100	. mV
Load regulation	rteg ibau	1 mA≤ lo≤ 40 mA			13	50	
	1		25°C		4.3	6.5	
Bias current	B		125°C			6	mA
Bias current change	∆I _B	16≤ VI≤ 27V	-40 ~ 125℃			1.5	m A
Dias current change	ΔıΒ	1 mA≤ lo≤ 40 mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kt/z	25°C		70		μN
Ripple rejection	RR	15≤ VI≤ 25V f=120 Hz	25℃	37	42		dB
Dropout voltage	VD		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L15 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=19V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test condi	Test condition *		Тур.	Max.	Unit
			25°C	14.4	15	15.6	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 17.5V≤ VI≤ 30V	-40 ~ 125℃	14.25	15	15.75	v
		1 mA≤lo≤ 70 mA		14.25	15	15.75	
Line regulation	Reg line	17.5≤ VI≤ 30V	25℃		65	300	mV
Line regulation	Regime	19≤ VI≤ 30V			58	250	mv
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25℃ .		25	150	. mV
Load regulation	Neg load	1 mA≤ lo≤ 40 mA			15	75	
	1		25°C		4.2	6.5	
Bias current	B		125°C			6	mA
Bias current change	ΔI _B	19≤ VI≤ 30V	-40 ~ 125℃			1.5	۳۸
blas current change	ΔB	1 mA≤ lo≤ 40 mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kHz	25°C		82		μN
Ripple rejection	RR	18.5≤ VI≤ 28.5V f=120 Hz	25°C	37	44		dB
Dropout voltage	VD		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L18 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=23V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25°C	17.3	18	18.7	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 20.5V≤ VI≤ 33V	-40 ~ 125℃	17.1	18	18.9	V
		1 mA≤lo≤ 70 mA		17.1	18	18.9	
Line regulation	Reg line	20.5≤ VI≤ 33V	25°C -		70	360	m\/
	Regime	22≤ VI≤ 33V			64	300	mV
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25℃ .		27	180	mV
	Neg load	1 mA≤ lo≤ 40 mA			19	90	
	I		25°C		4.7	6.5	
Bias current	B		125°C			6	mA
Bias current change	∆I _B	22≤ VI≤ 33V	-40 ∼ 125°C			1.5	۳۸
bias current change	11	1 mA≤ lo≤ 40 mA	-40 ~ 123 0			0.1	- mA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kHz	25°C		82		μN
Ripple rejection	RR	21.5≤ VI≤ 31.5V f=120 Hz	25°C	32	36		dB
Dropout voltage	VD		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.



HT78L24 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=26V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test condi	ition *	Min	Тур.	Max.	Unit
			25°C	23	24	25	
Output voltage **	Vout	1 mA≤ lo≤ 40 mA 26.5V≤ VI≤ 39V	-40 ~ 125℃	22.8	24	25.2	V
		1 mA≤lo≤ 70 mA		22.8	24	25.2	
Line regulation	egulation Reg line 26.5≤ VI≤ 39V 25°C 29≤ VI≤ 39V		95	480	mV		
Line regulation			78	400	IIIV		
Load regulation	Reg load	1 mA≤ lo≤ 100 mA	25°C		41	240	mV
Load regulation	iteg load	1 mA≤ lo≤ 40 mA			28	120	
	I		25°C		4.8	6.5	
Bias current	B		125°C			6	mA
Bias current change	∆I _B	28≤ VI≤ 39V	-40 ~ 125℃			1.5	۳۸
bias current change	1	1 mA≤ lo≤ 40 mA	-40 ~ 125 0			0.1	mA
Output noise voltage	V _N	10 Hz≤ f≤ 100 kHz	25°C		82		μN
Ripple rejection	RR	27.5≤ VI≤ 37.5V f=120 Hz	25℃	30	33		dB
Dropout voltage	VD		25°C		1.7		V

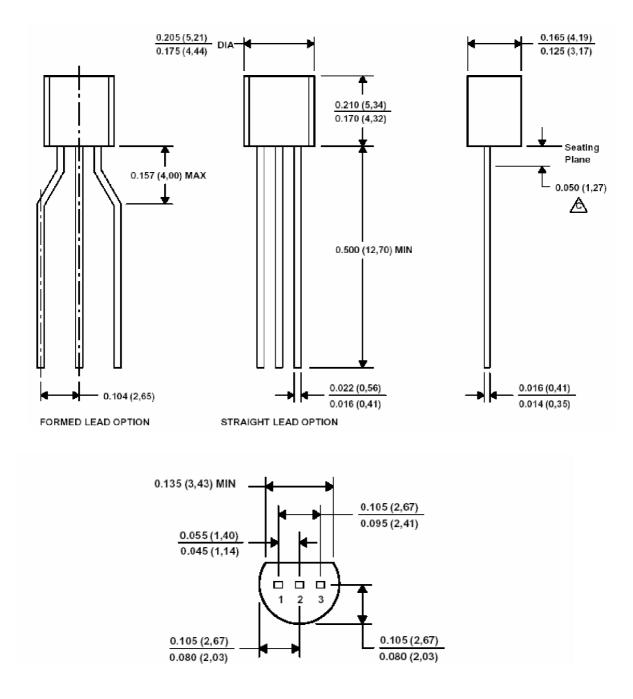
Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33 μ F capacitor across the input and a 0.1 μ F capacitor across the output.

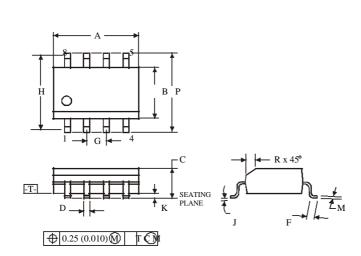


• TO-92





• SO-8



D SUFFIX SOIC (MS - 012AA)



	Dimension, mm	
Symbol	MIN	MAX
Α	4.8	5
В	3.8	4
С	1.35	1.75
D	0.33	0.51
F	0.4	1.27
G	1.27	
Н	5.72	
J	0 °	8 °
K	0.1	0.25
М	0.19	0.25
Р	5.8	6.2
R	0.25	0.5

NOTES:

- 1. Dimensions A and B do not include mold flash or protrusion.
- 2. Maximum mold flash or protrusion 0.15 mm (0.006) per side for A; for B 0.25 mm (0.010) per side.

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